

Welcome to  
7718 semester 1 2022  
Mixed Signal Electronic Circuits

Instructor: Dr. Miki Moyal



## Lecture 7

**SUCCESSIVE APPROXIMATION ADC: Operation**

**Design of Time Continuous SARs**

**Design of Switch C SAR**

**Error sources**

Lectures are placed in my site:  
<http://www.gigalogchip.com/lectures.html>

## Agenda

- ADC Architectures
- SAR ADCs
- Error Sources

### A/D Converter ca. 1954

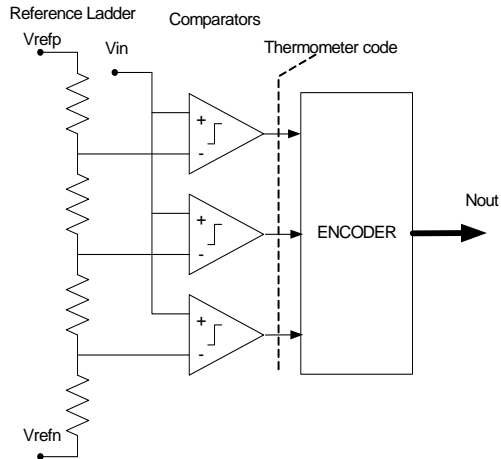
- ◆ 19" × 15" × 26"
- ◆ 150 lbs
- ◆ 500W
- ◆ \$8,500.00



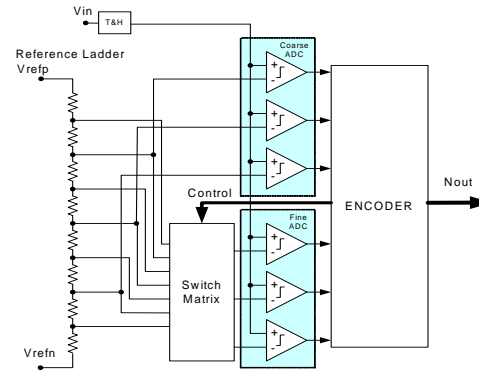
Courtesy,  
Analogic Corporation  
8 Centennial Drive  
Peabody, MA 01960  
<http://www.analogic.com>

*Figure 4.3: 1954 "DATRAC" 11-bit, 50-kSPS SAR ADC  
Designed by Bernard M. Gordon at EPSCO*

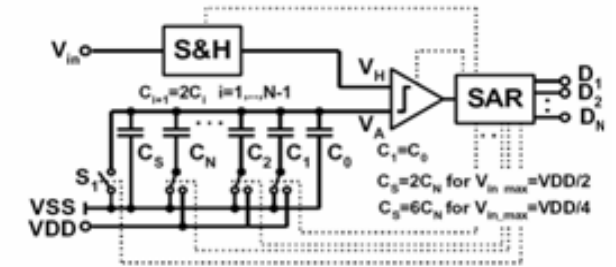
# Common data acquisition architectures



FLASH ADC

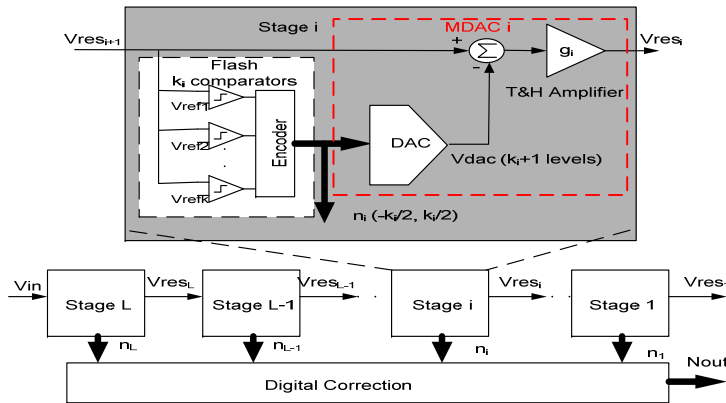


Sub ranging

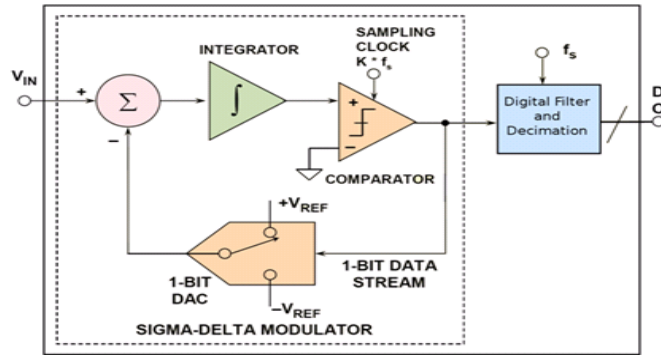


With S/H

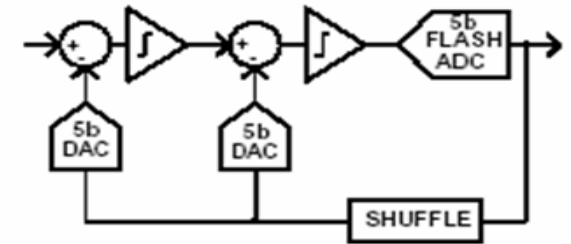
SAR



De Pipe Line



Sigma Delta



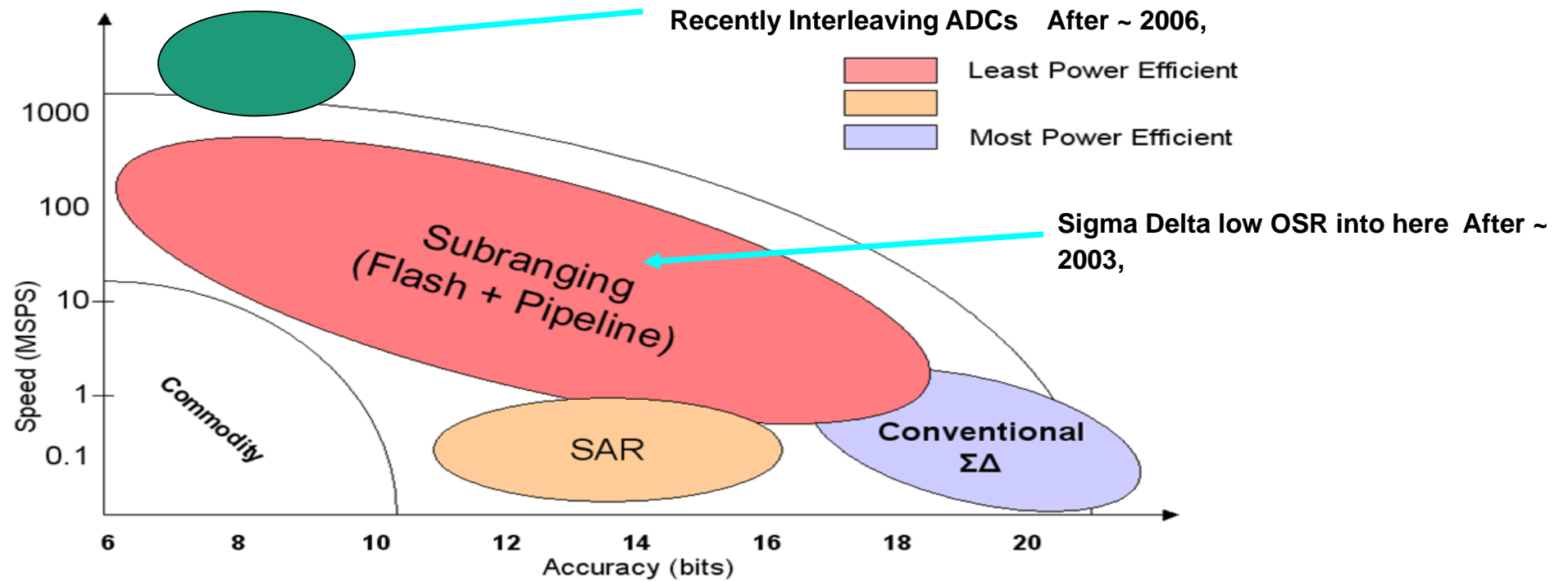
SD multi bits

# Which ADC to use and why

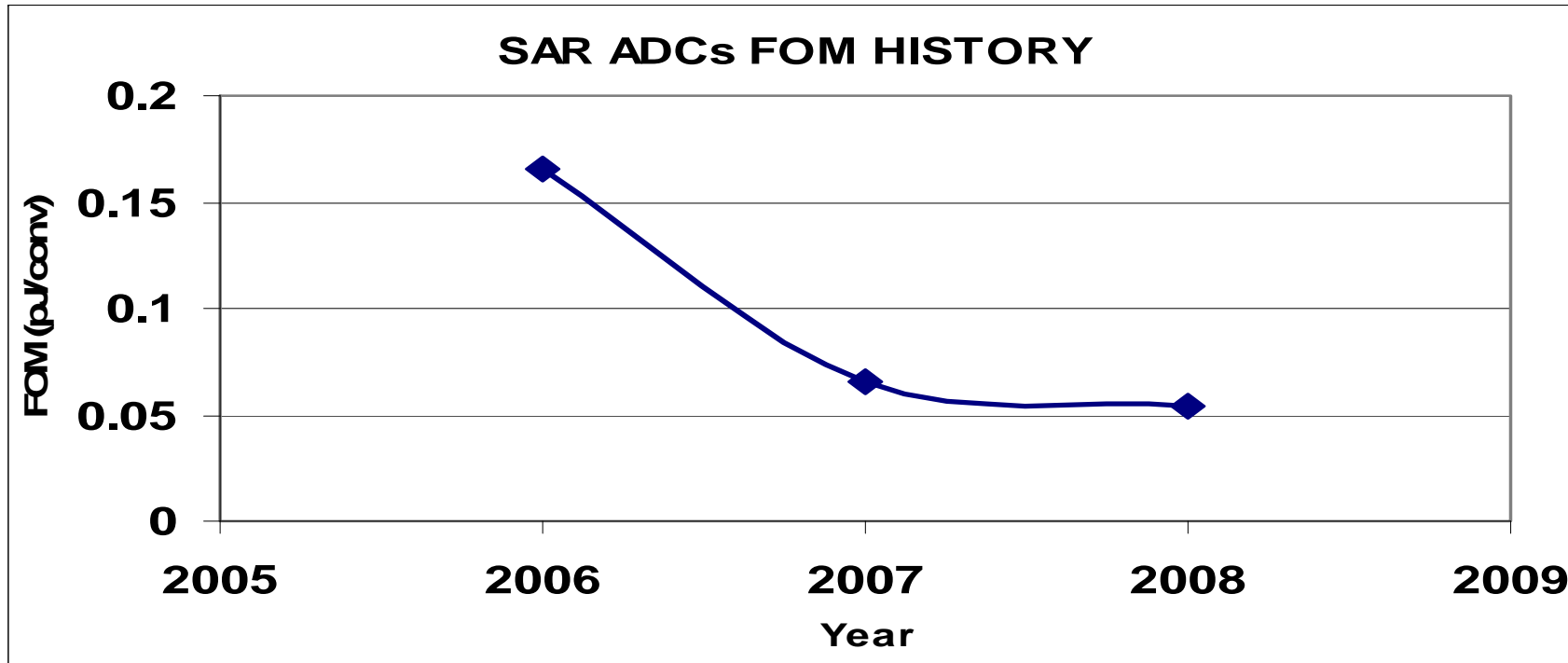
miki

Technion

## ADC Architectures



## SAR ADC FOM History



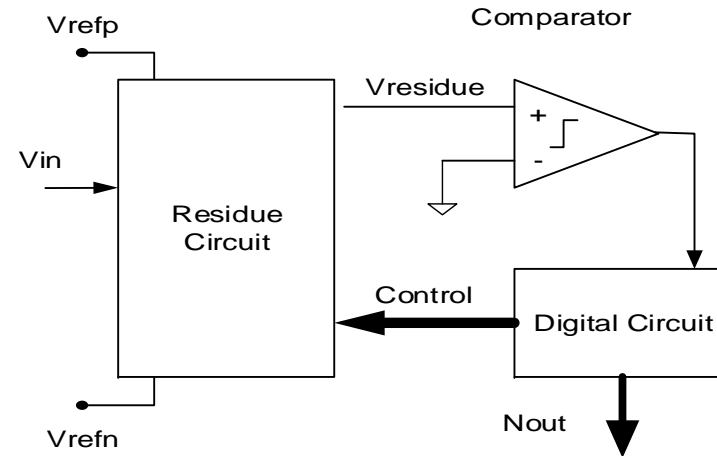
2006 → 12b & 100Ks/s (180nm CMOS)

2007 → 9b & 50Ms/s (90nm CMOS)

2008 → 9b & 40Ms/s (90nm CMOS)

$$\frac{\text{Energy}}{\text{Decision}} = \frac{\text{Power}}{\text{SamplingRate} \times 2^{Nbit}}$$

## Generic ADC:



- ❑  $V_{\text{residue}}$  is a function of  $V_{\text{in}} - V_{\text{ref}}$  .
- ❑ The Residue sets the source of Linearity Errors
- ❑ The Comparator set the source Speed (Offset may be a problem )
  
- ❑ Must check always:
  - ❑ Distortion (non linearity's) and ckt noise.
  - ❑ Speed and Power

## Successive approximation ADC

If  $T_s$  is twice maximum BW

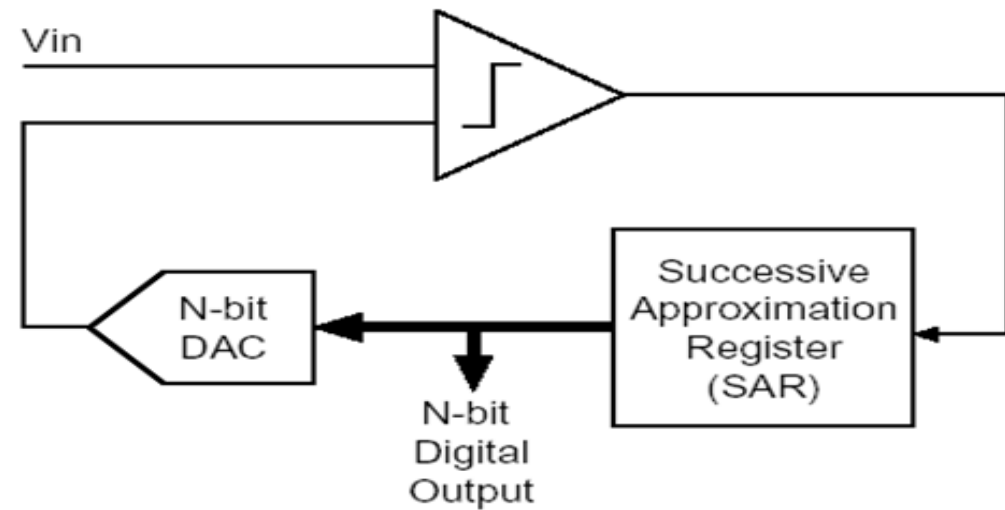
And if  $N$  =desired bits

It requires minimum of  $p = N \times T_s$  passes to generate  $N$  bit

Output words limiting the through put

It requires  $N$ -bit accurate DAC

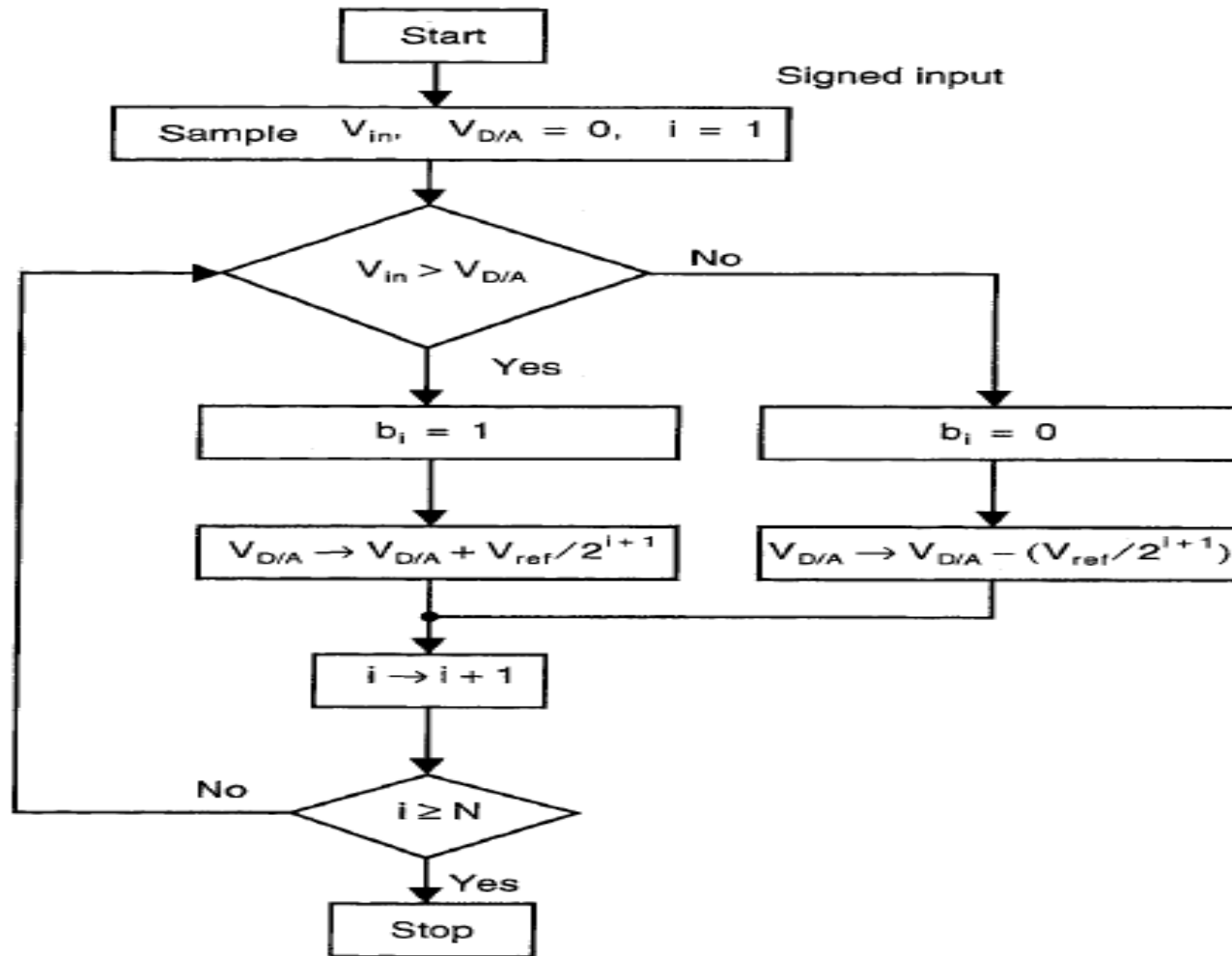
It requires faster settling elements



Strict timing is involved- transforming analog to digital each cycle

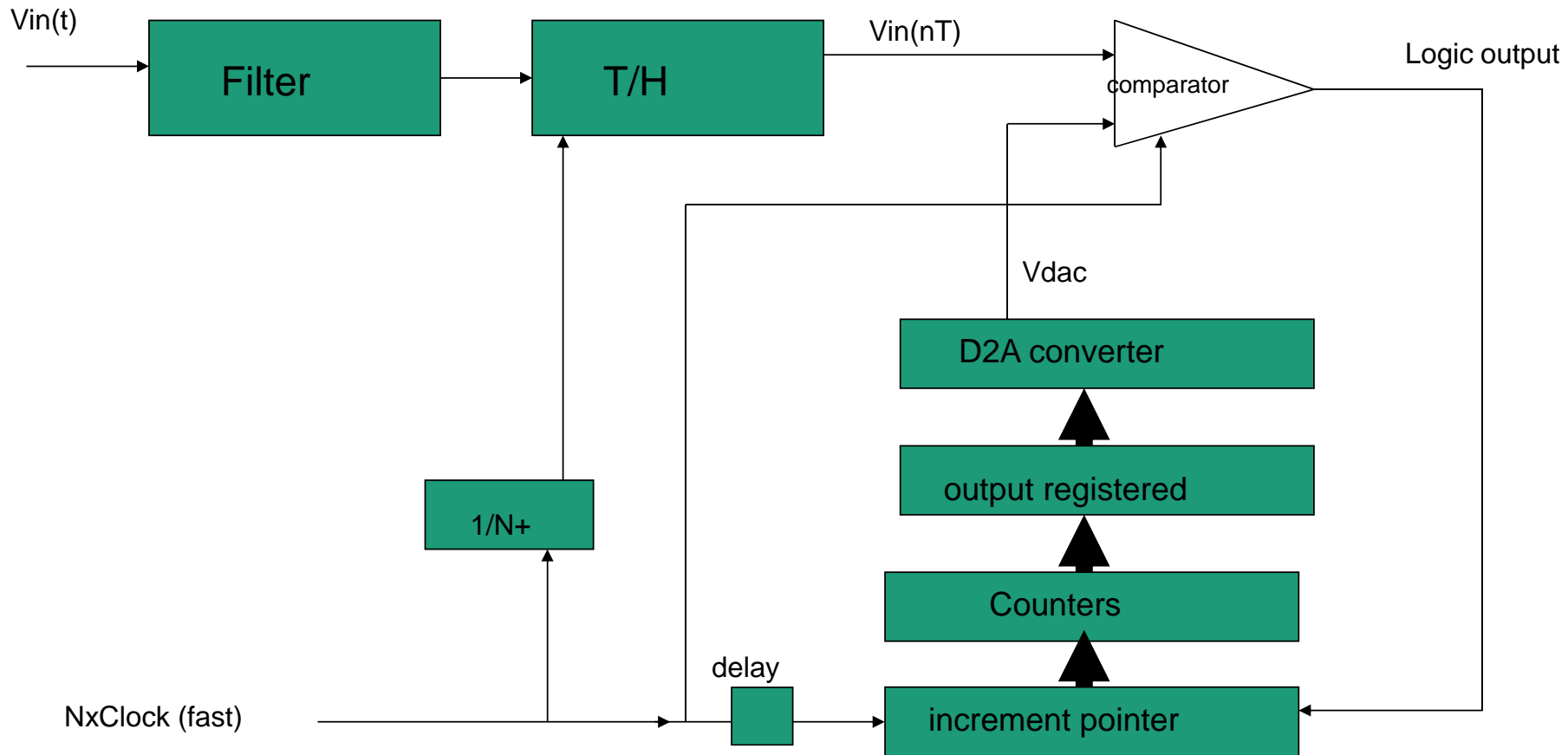
Comparator runs inside an open loop circuit  
therefore stability and closed loop Band width is not an issue.

# Flow chart of SAR ADC

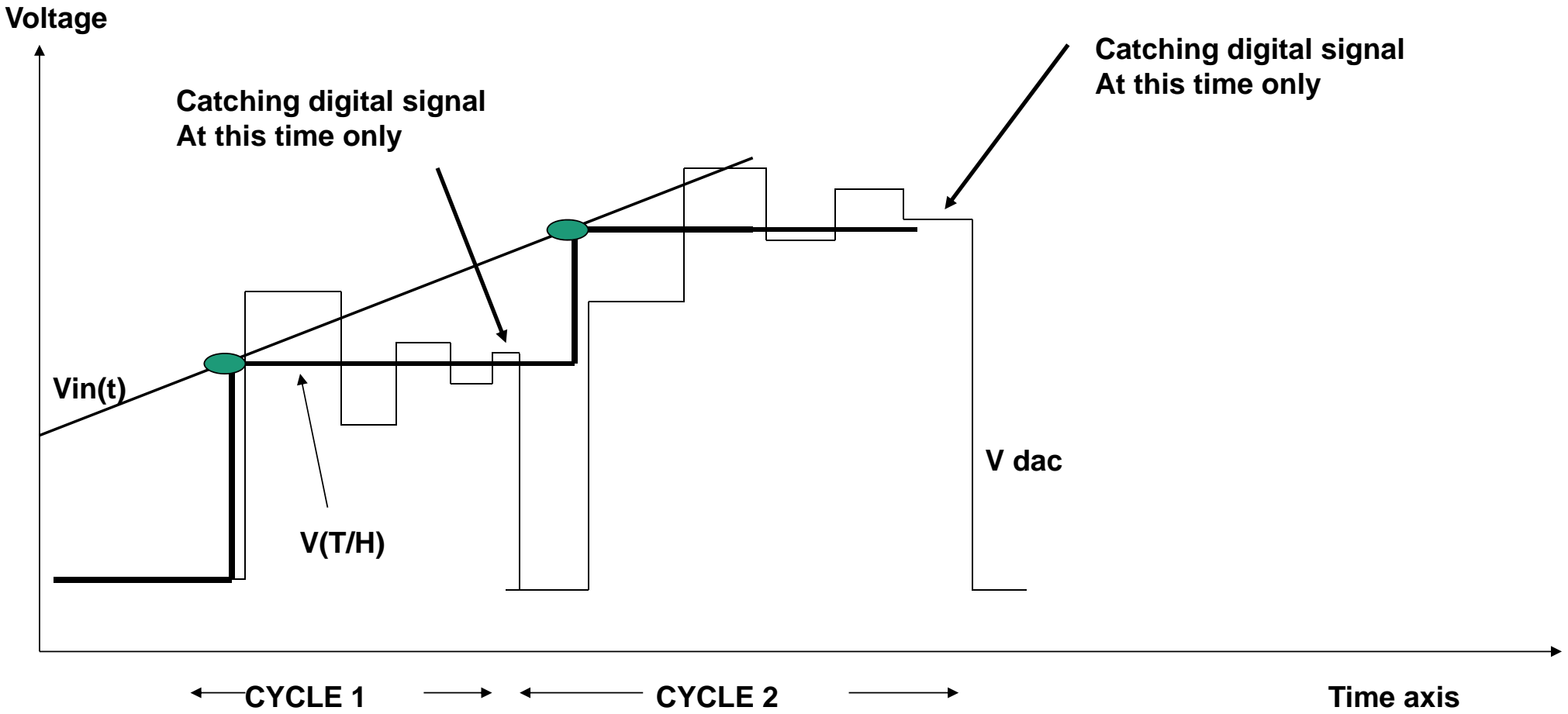




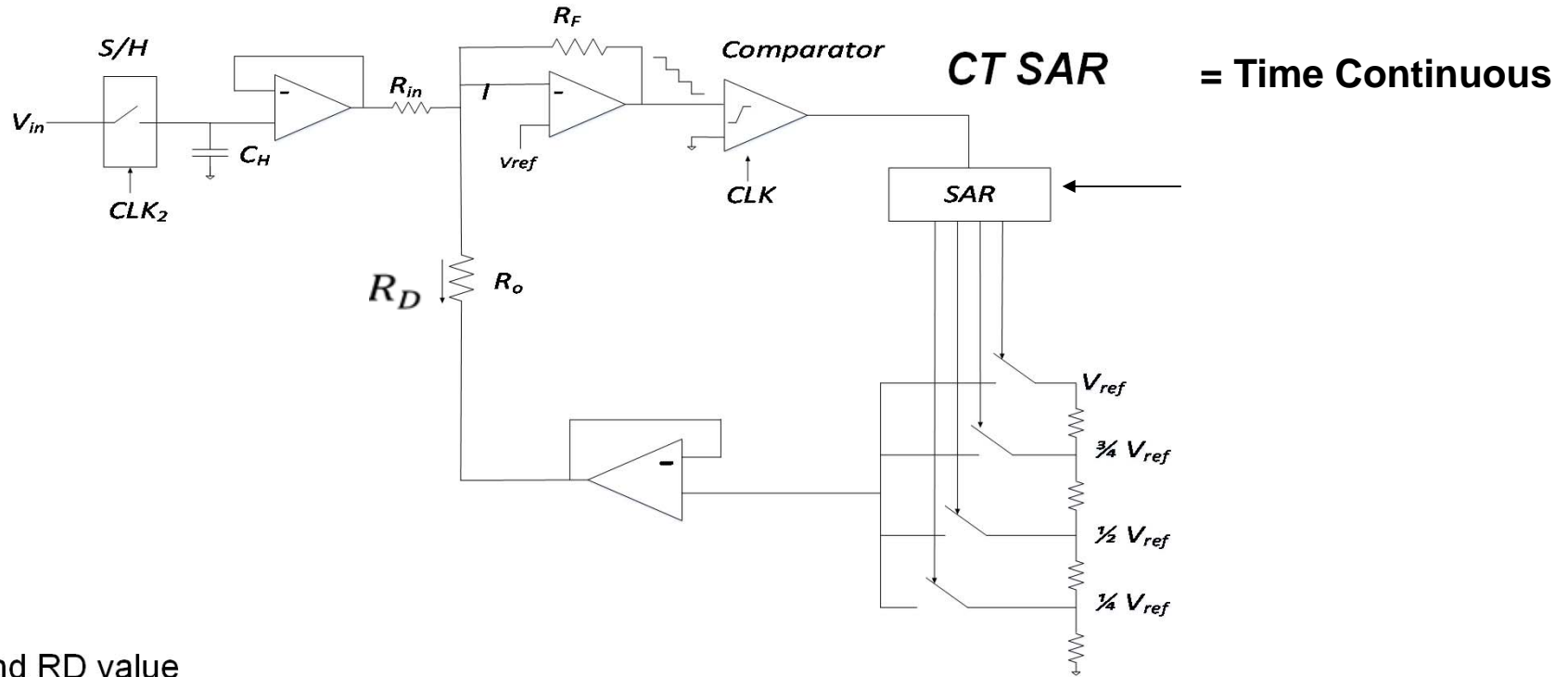
# SAR ADC Details



# SAR ADC – Timing



## SAR design- determining full scale



Continuous,  
w. sub tractor

How to find RD value

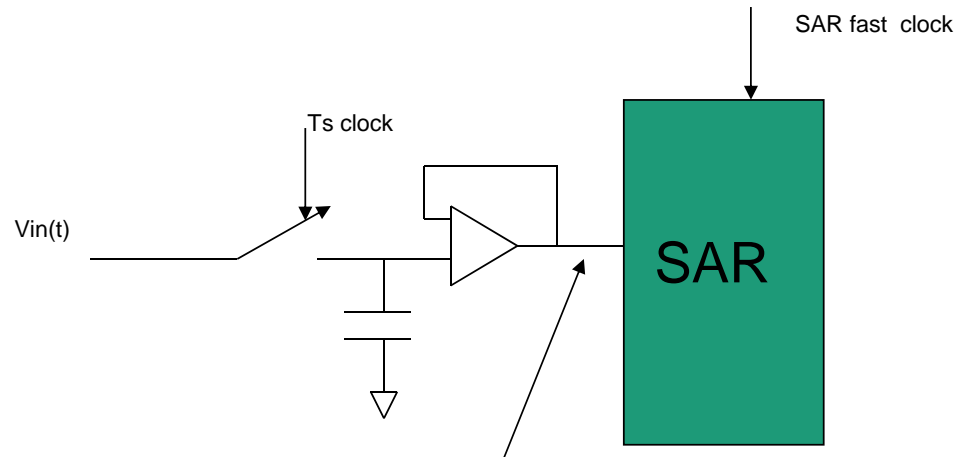
$$R_D \gg \frac{V_{in\_max}}{R_{in}} = \frac{V_{ref}}{R_D}$$

$$R_D = \left[ \frac{V_{in\_F.scale}}{V_{ref}} \right]^{-1} R_{in}$$

Time Continuous only means we use non switched C for dac

## Time continuous SAR block

### 1<sup>st</sup> step sample and hold

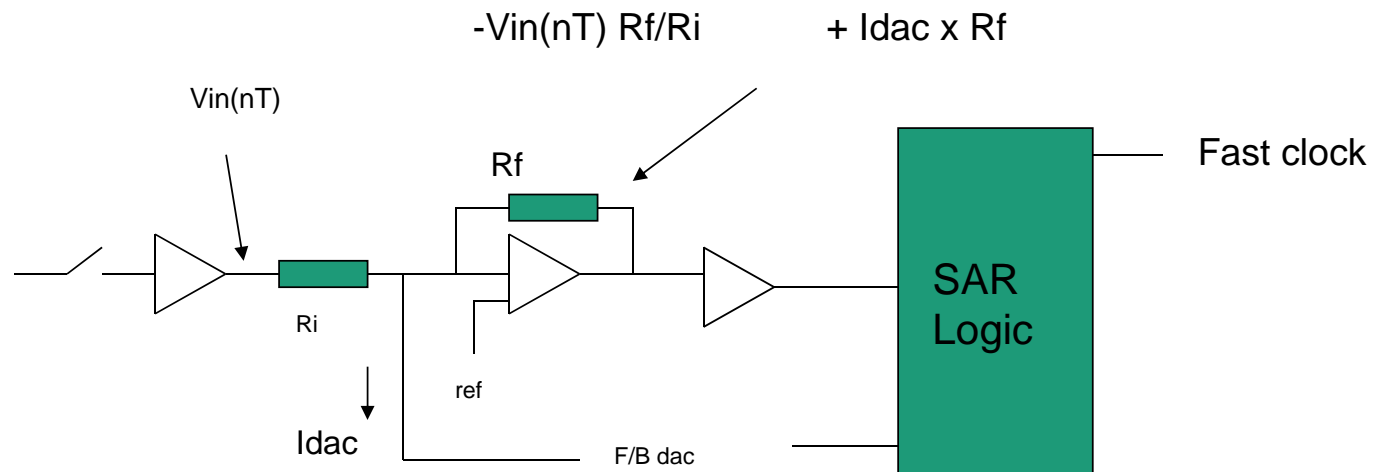


Covered already. Note the buffer

- We know the errors
- We know the speed needed
- We can proceed to build the block

## SAR analog Loop

□ 2<sup>nd</sup> step the sampled voltage part is being converted to I

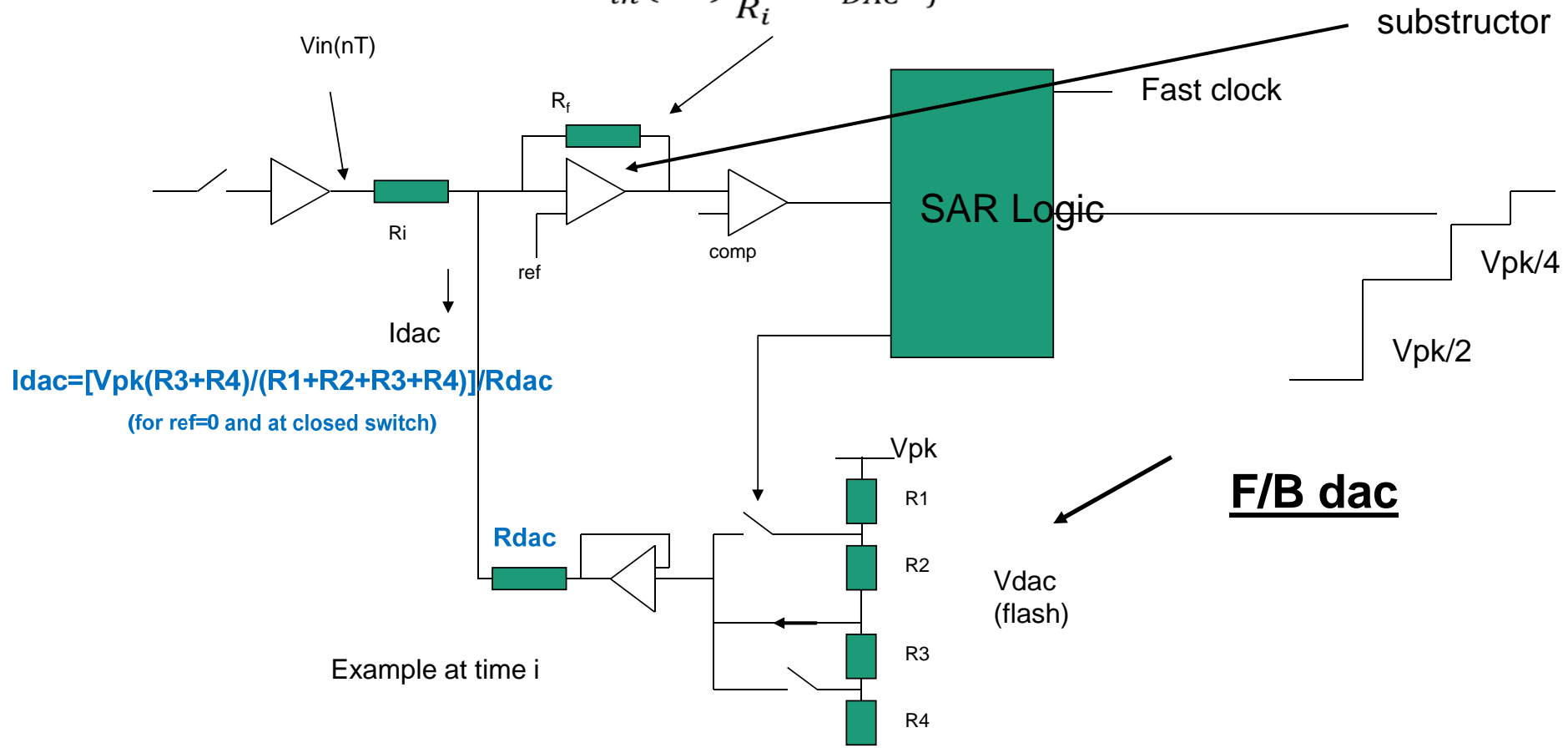


Next how to build IDAC

## SAR IDAC feedback generation

□ 3<sup>rd</sup> step the  $I_{in}$  and  $I_{dac}$  is compared around the loop  $n$  times

$$-V_{in}(nT) \frac{R_f}{R_i} + I_{DAC} R_f$$

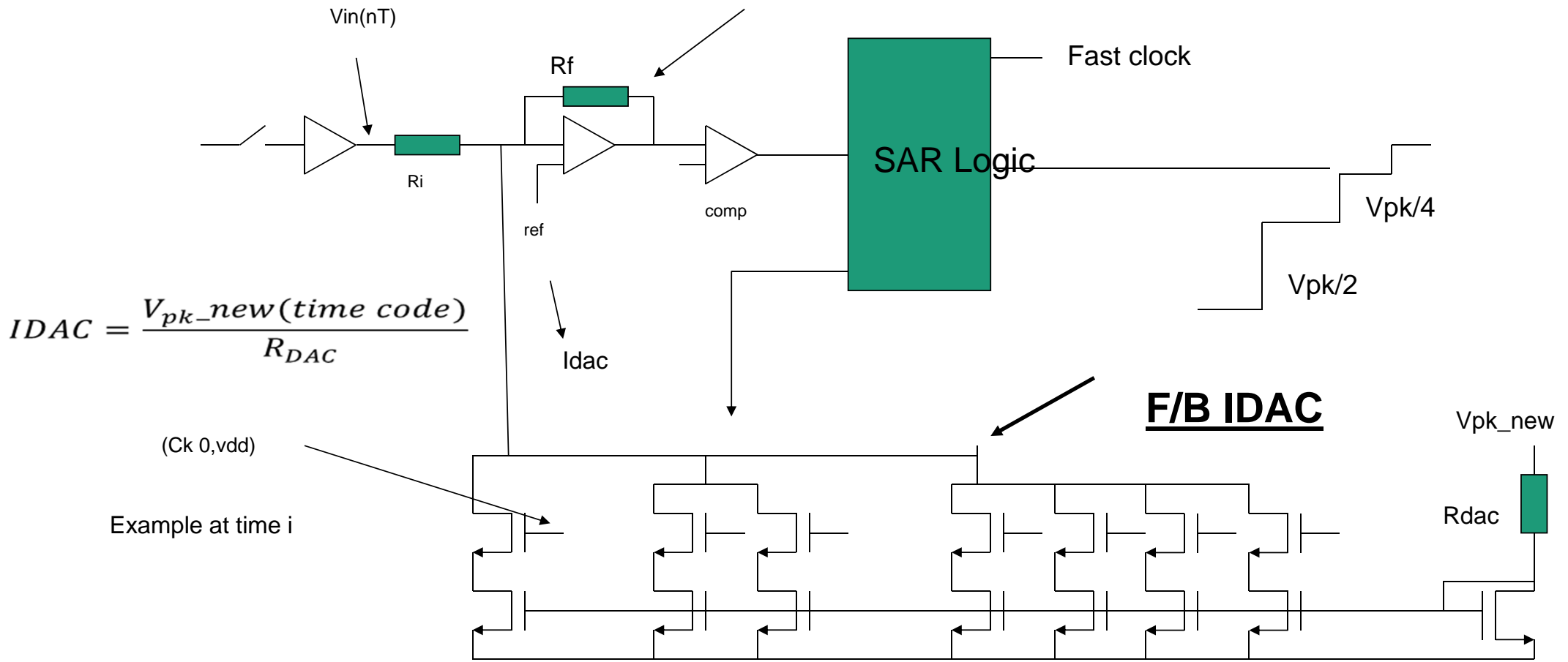


## SAR DAC – use an another alternative to R-Ladder

- Go to DAC lecture pick another type ?
- We got transistors they are small
- Current is always easy to generate with transistors

## SAR DAC – another DAC – speed and area Improvement

$$-V_{in}(nT) \frac{R_f}{R_i} + I_{DAC} R_f$$





## SAR DAC – another DAC – speed and area Improvement

- We used “not so efficient design”
  
- Speed issues:
  - BW amplifier,
  - Subtraction with amplifier
  - S/H - or Track and Hold.
  - Area
  
- Can we do it other way?
- Lead to a simpler architecture
- No amplifiers !
- With capacitors we can easily subtract**
- Speed per cycle may be faster

## SAR DAC – another DAC – speed and area Improvement

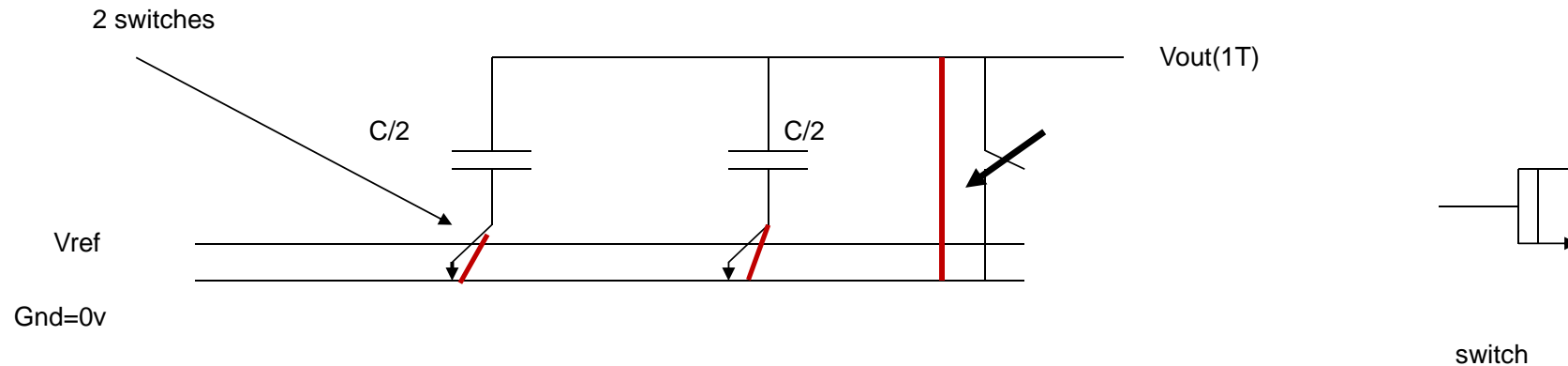
We want to generate

|                                         |                             |
|-----------------------------------------|-----------------------------|
| $V_{ref}/2$ .....                       | 1 <sup>st</sup> clock cycle |
| $V_{ref}/2 \pm V_{ref}/4$ ..            | 2 <sup>nd</sup> clock cycle |
| $V_{ref}/2 \pm V_{ref}/4 \pm V_{ref}/8$ | 3 <sup>rd</sup> clock cycle |
| Etc...., ,                              |                             |

So lets use capacitor DAC to do this.

## Charge Distribution SAR DAC Operation

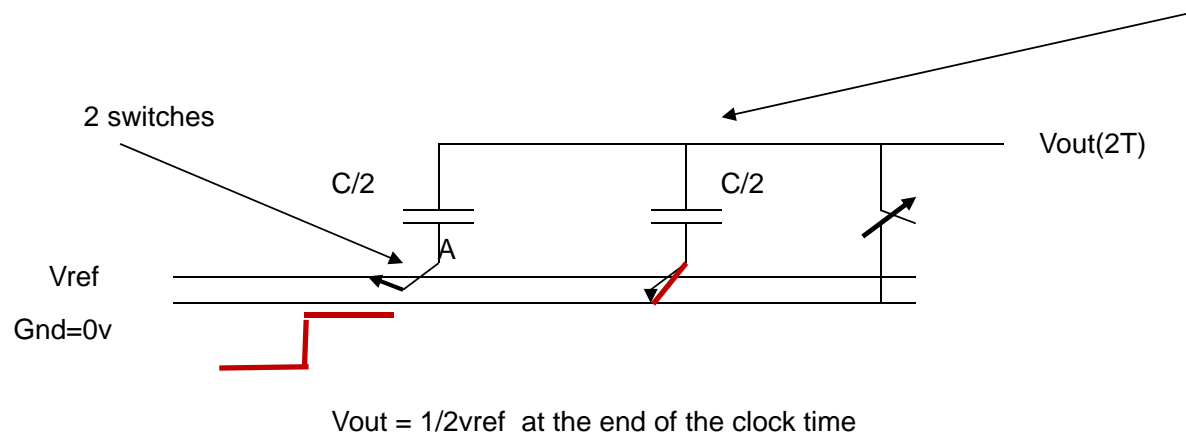
Step 1.- clock n=1, reset everything to 0 point – “wasted state” but needed because capacitors plates are held at a “value” for DC



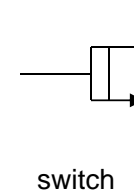
$V_{out} = 0v$  all capacitors plates are shorted to 0  
 In reality after  $nR_{on}C/2$  time ( $R_{on}=1/u_{cox}(v_{gs}-v_t)(w/l)$ )

## Generate $V_{ref}/2$ to Compare

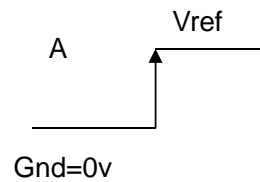
Step 2.- clock n=2, generate  $v_{ref}/2$  to compare with input



Voltage divider action



Point A



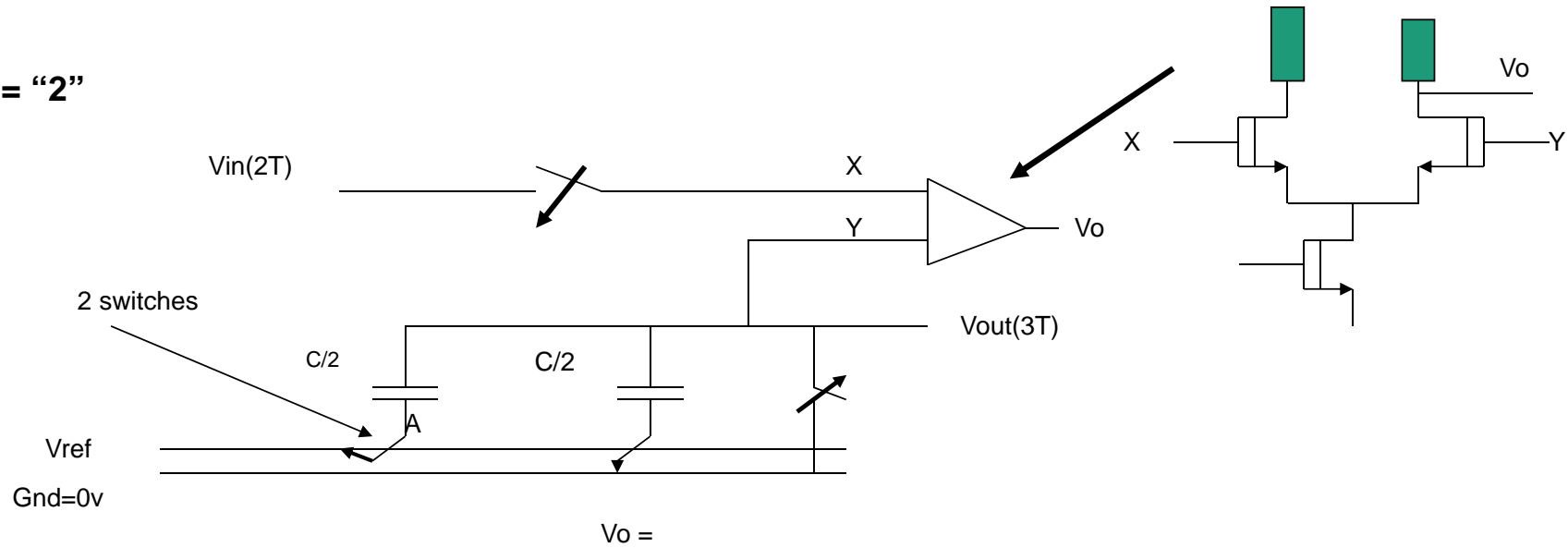
$$V_{out}(2T) = 0 + \frac{1/S0.5C}{(1/S0.5C + 1/S0.5C)} V_{ref}$$

$$V_{out}(2T) = \frac{1/0.5}{(1/0.5 + 1/0.5)} V_{ref}$$

$$\mathbf{V_{out}(2T) = V_{ref}/2}$$

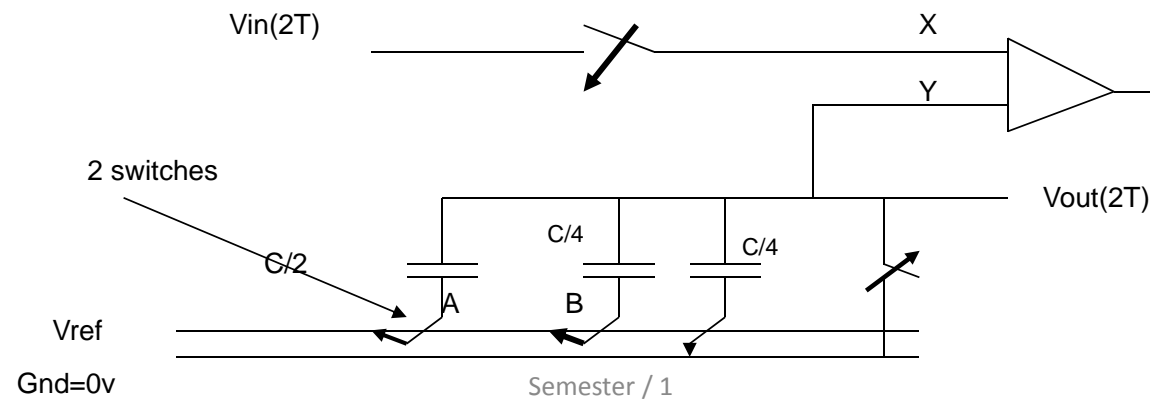
# Compare to $V_{ref}/2$ and Generate $V_{ref}/2 + V_{ref}/4$

still in time = "2"

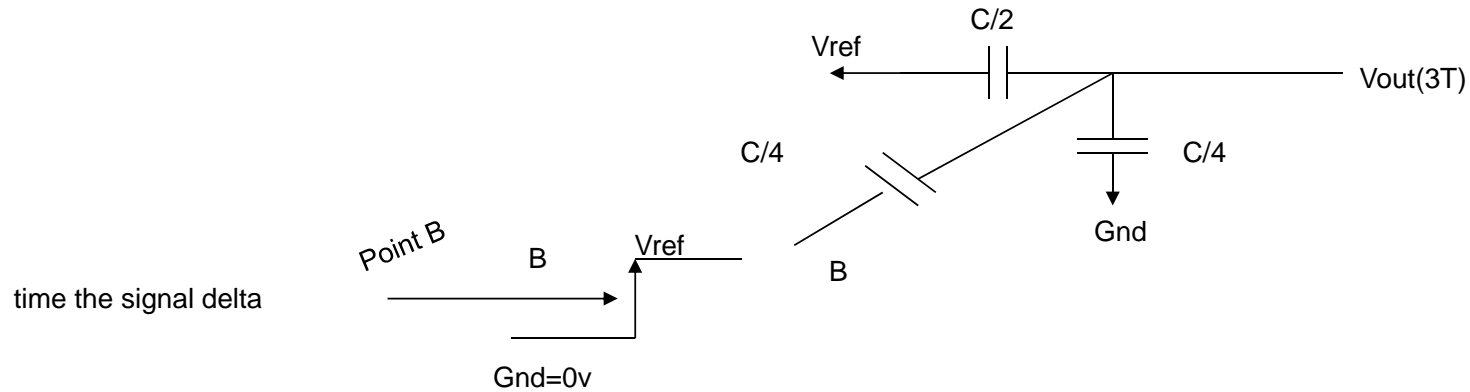


in time = "3" add  $1/4$  vref

Re arrange C to units



## Generate $V_{ref}/2 + V_{ref}/4$



$$\Delta V_{out}(3T) = (0.25C / C) V_{ref}$$

$$\Delta V_{out}(3T) = 1/4 \text{ (time the signal delta)}$$

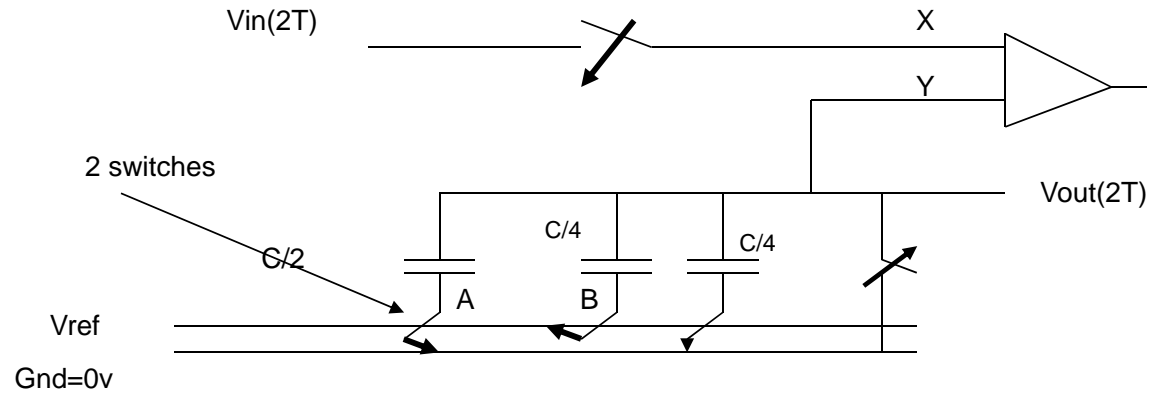
$$V_{out}(3T) = V_{ref}(2T) + 1/4 V_{ref}$$

$$\mathbf{V_{out}(3T) = V_{ref}/2 + V_{ref}/4}$$

Generate the Minus  $\rightarrow V_{ref}/2 - V_{ref}/4$

in time = "3" add  $-1/4 vref$

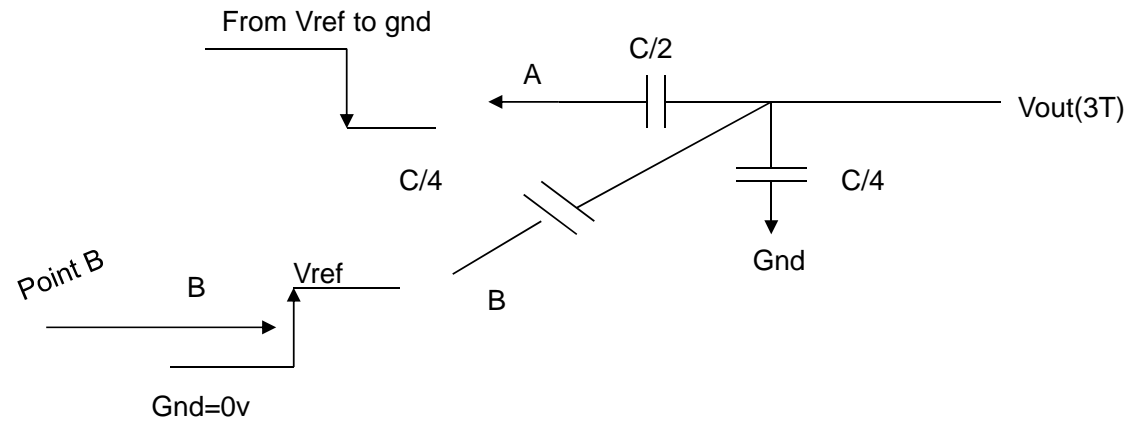
2 operations



$$\Delta V_{out}(3T) = -0.5 + 0.25$$

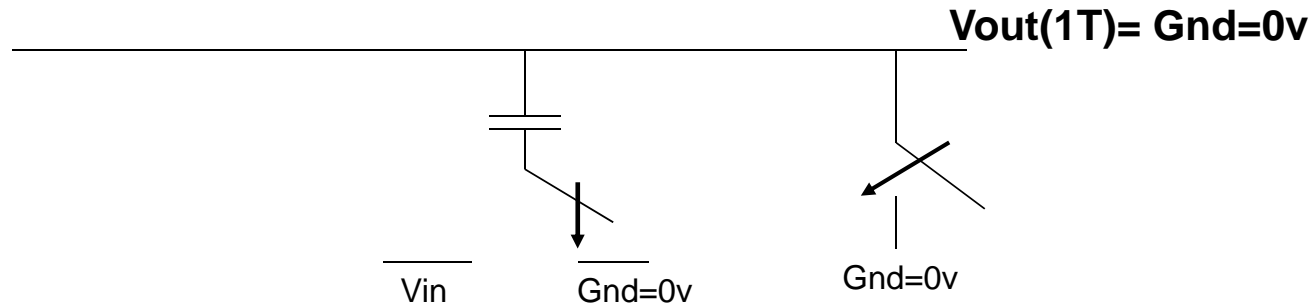
$$V_{out}(3T) = V(2T) + -0.5 + 0.25$$

$$\Delta V_{out}(3T) = 1/4 V_{ref}$$

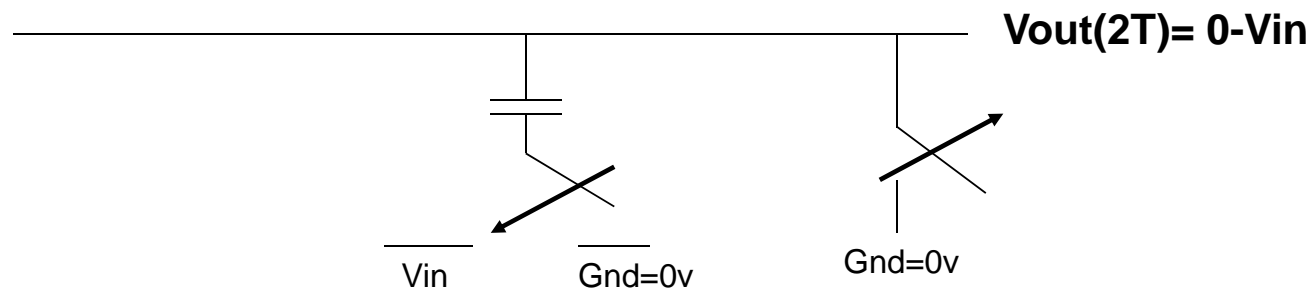


## Generate the Minus of the Input as well Easily

$T=1$



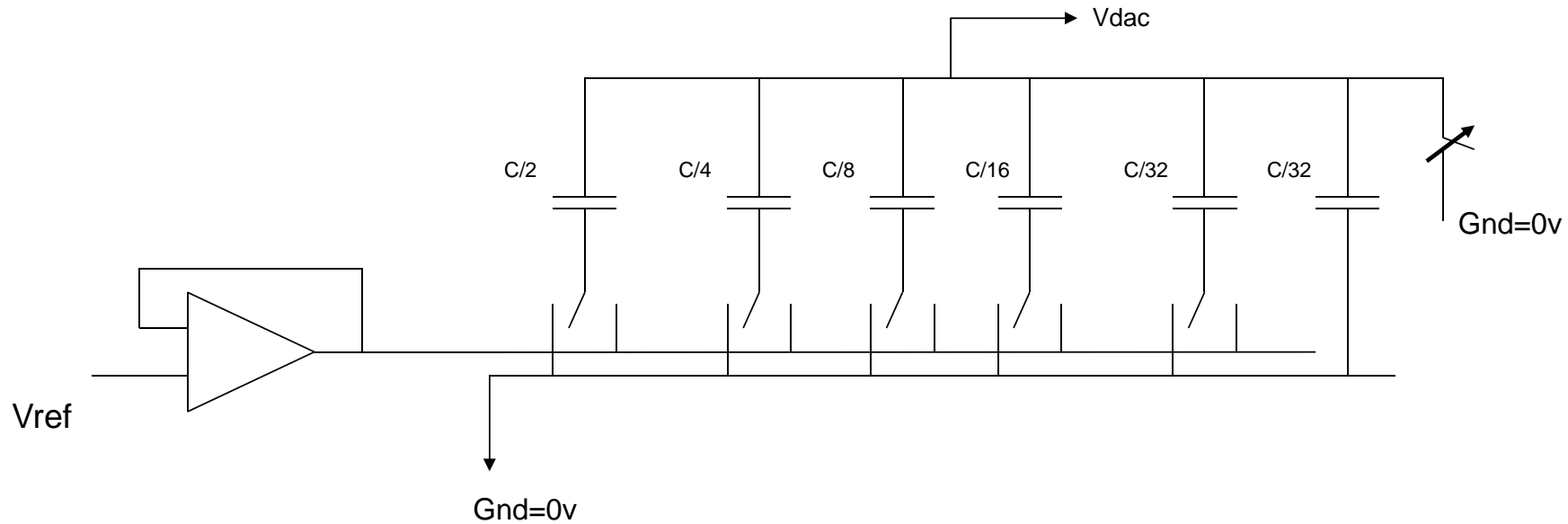
$T=2$



And on.. And on.. Until the number of bits  $M+1$



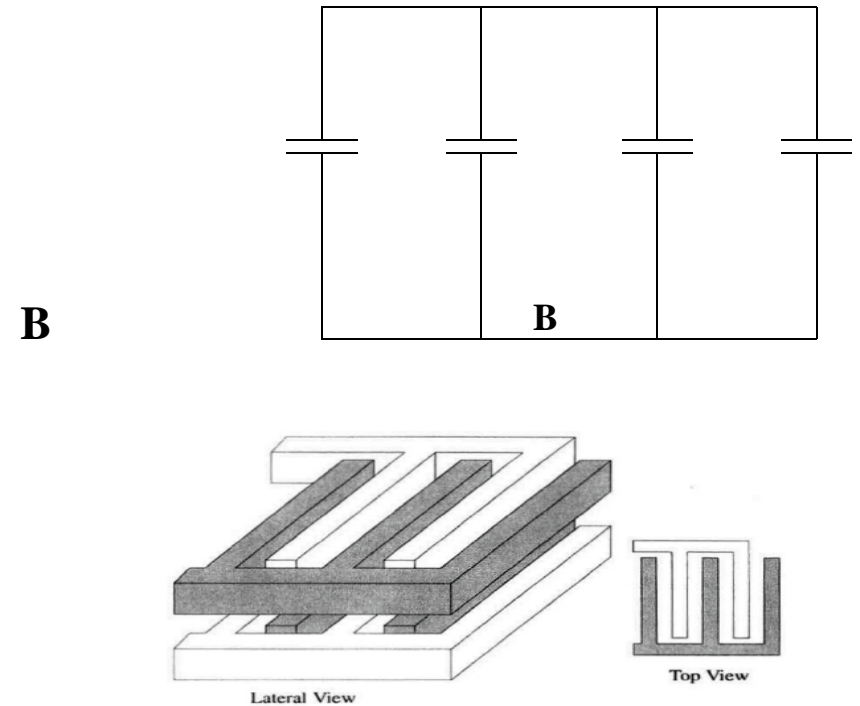
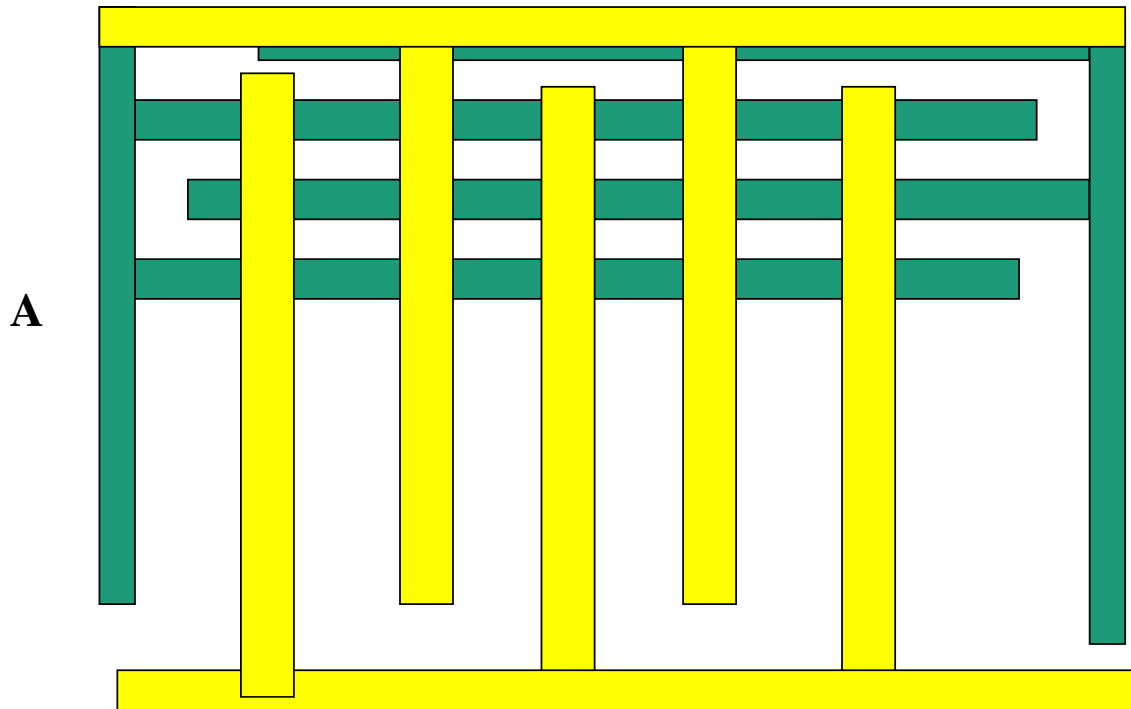
.... Let's Look at complete C-DAC SAR



**5bit dac**

**Fring. Caps to improve area density (capacitors on IC)**

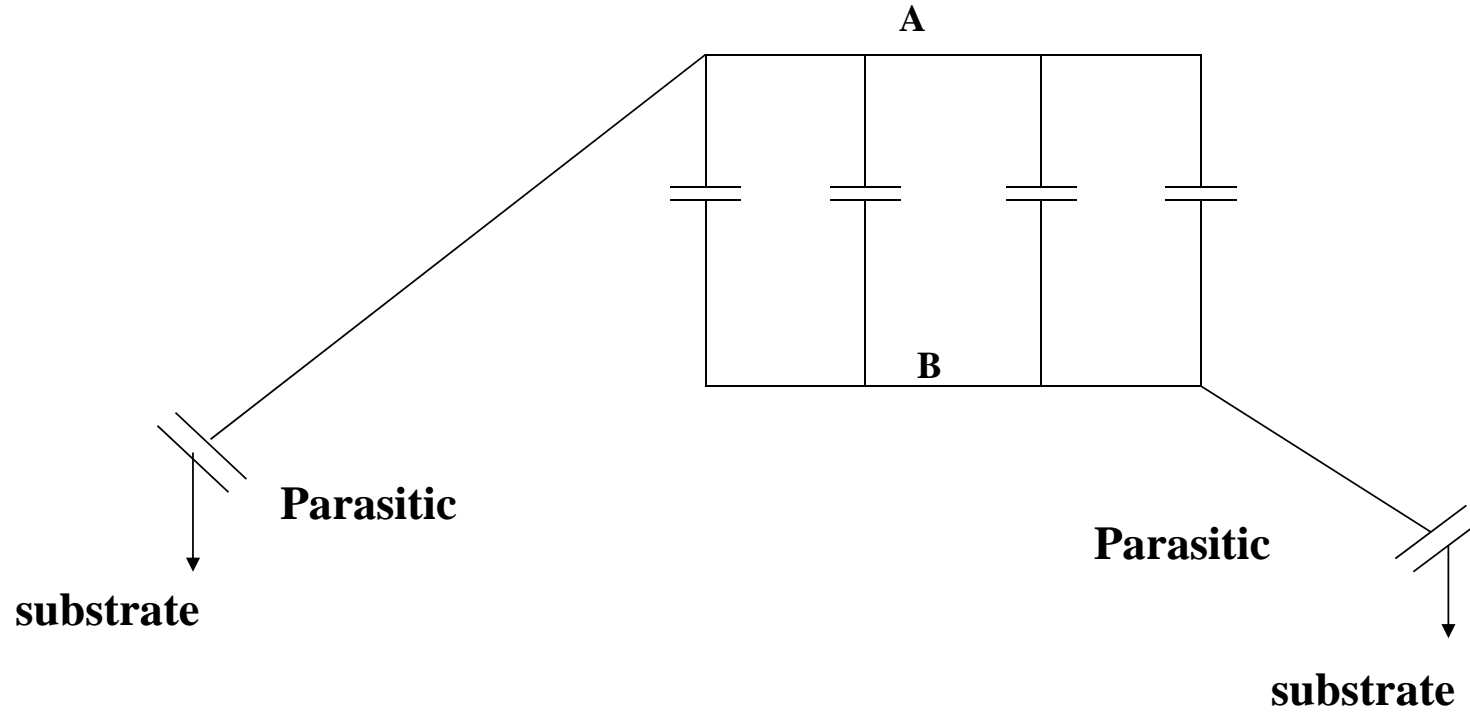
$$C = C_o WL \longrightarrow \bar{C} = C_o WL + 2C_{fr} (W + L)$$



Accuracy in silicon is low ~ +/-20%  
 Low temperature/V dependency  
 Matched well. What about plate parasitic ?

$C_o = 1-2 \text{ ff/uu}$  if Metal to Metal sandwiched  
 With Fringing effect into the picture:

## Fring. Capacitors-Parasitic Errors



**C parasitic ~0.1-0.2C total! – how to design it out..**

## Silicon Transistors as Capacitors

### Capacitors from MOS (transistor) → triki.- watch the plates potential.

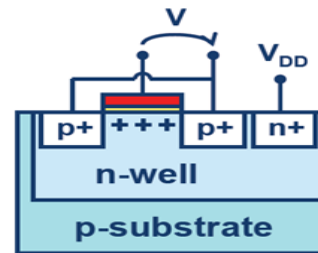
In accumulation (off) →  $V_{gs} < V_t$  (n ch)

$$C = C_o WL$$

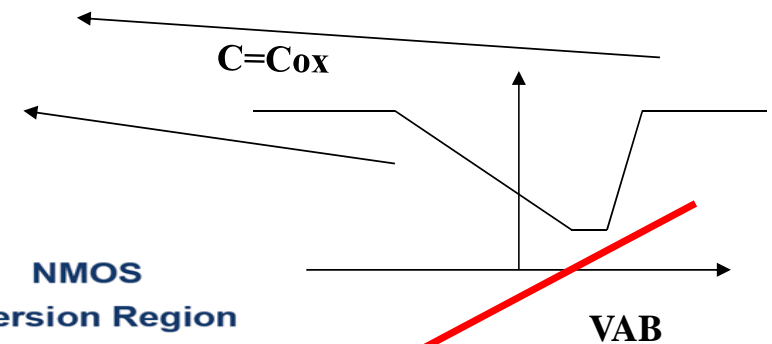
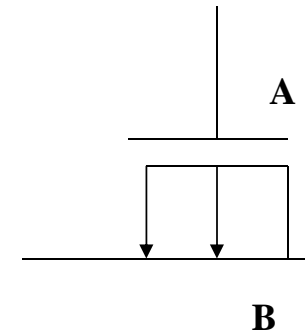
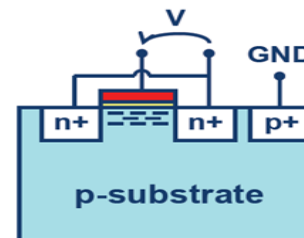
$C_o \sim 12\text{ff}$  if thin oxide is used (90nm)  
 Cap is to the substrate (N well probably)  
 In depletion (on) →  $V_{gs} > V_t$

Cap is to the drain sources!  
 Next to  $V_t$  – C drops to  $\sim 0.3$  its max value  
 It's a voltage dependent capacitor –  
 doesn't work good with 0 volt across it (integrator and opamp)

P can be in both

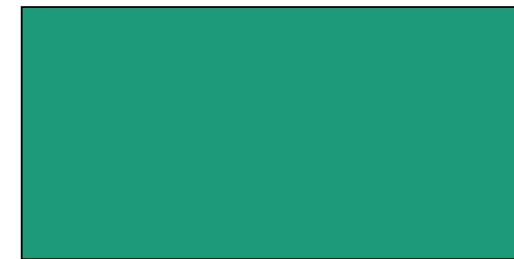
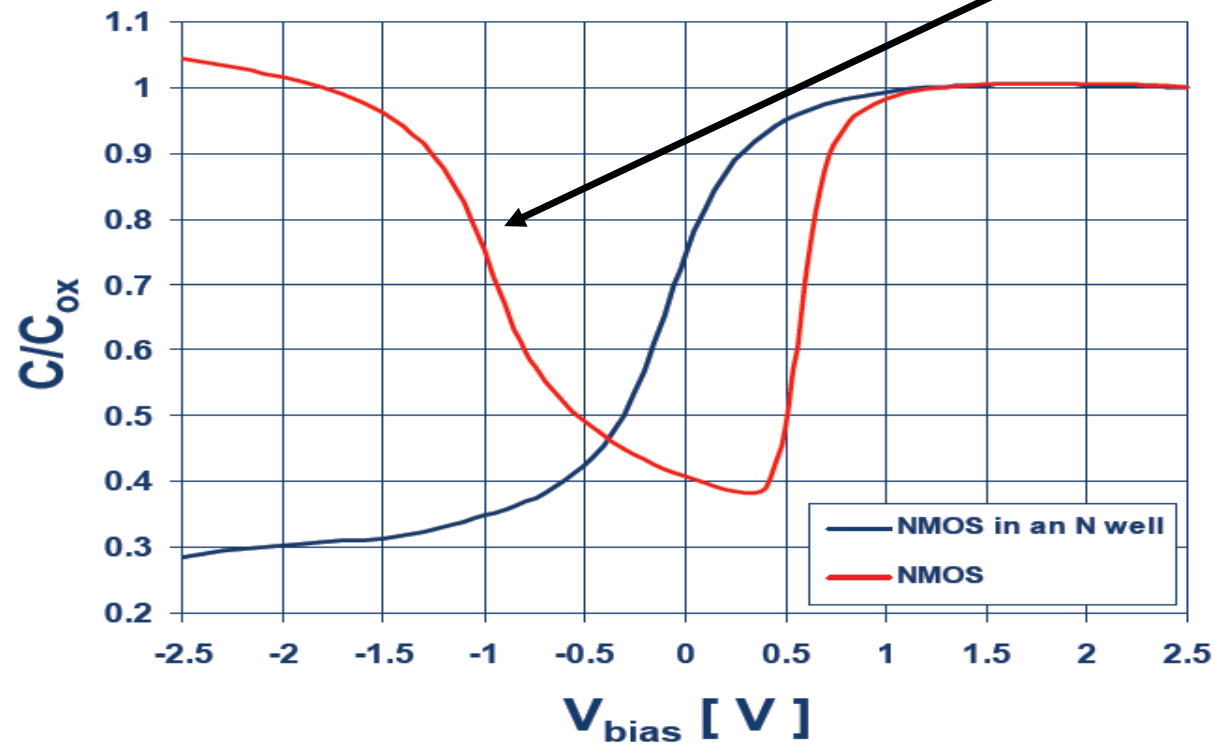


NMOS Inversion Region



# Silicon Transistors as Capacitors

Why not work here ? – ah.. Veractor..



The NMOS capacitor is in inversion for  $V > 0$ .

Giovanni Anelli, CERN

## Errors in SAR ADCs

- ❑ Its an accurate structure
- ❑ Subtraction using caps
- ❑ Low/average power: SH, one comparator, DAC, and Logic
- ❑ 8b-200msps is possible
- ❑ But: Need Accuracy in the DAC.
- ❑ Comparator offset  $< \sim 0.5$  LSB – Easily calibrated

## ***ACCURACY : FUNCTION OF DAC (CAPACITORS) MATCHING***

## Matching

$$C \approx \epsilon \frac{WL}{t} \longrightarrow \left( \frac{\Delta C}{C} \right)^2 = \left( \frac{\Delta \epsilon_r}{\epsilon_r} \right)^2 + \left( \frac{\Delta t_{\text{ox}}}{t_{\text{ox}}} \right)^2 + \left( \frac{\Delta L}{L} \right)^2 + \left( \frac{\Delta W}{W} \right)^2$$

- Once again can correlate to area with good accuracy
- How is it given

1. A\_ΔC/C is based on sigma of (ΔC / C) vs. 1/sqrt(WL)  
 typ. number 2fF/micron square

## Matching

**To get to the best matched number you need to :**

- ❖ Use identical geometries
- ❖ Use large unity capacitance (minimize fringing)
- ❖ Use common centroid arrangement
- ❖ Use dummy capacitors
- ❖ Use shielding
- ❖ Account for the connections' contribution
- ❖ Don't run connections over capacitor
- ❖ Place capacitor in low stress areas
- ❖ Place capacitors far from power devices



## An Example

Find the LSB capacitor size (and total capacitors) for a 12b SAR ADC Given that 10ff unit match to 0.8%. (to 1 sigma)

$$C_{unit} = 10fF \quad \left(\frac{\Delta C}{C}\right)_{unit} = 0.8\%$$

$$\Delta_{noise} = \sqrt{\frac{\Delta^2}{12} + [Distortions]^2 + \frac{KT}{C_T}}$$

$$1pF \sim 64E^{-6} V / \sqrt{Hz}$$

Let give  $[Distortions] \gg \frac{1}{3} LSB$  wight

$$\left[\frac{\Delta C}{C}\right]_{Full\ Scale} = \frac{1}{3} \left[\frac{1}{2^n - 1}\right] = 0.0081\%$$

$$\left[\frac{\Delta C}{C}\right]_{LSB} = [0.0081] \sqrt{2^n - 1} = 0.518\%$$

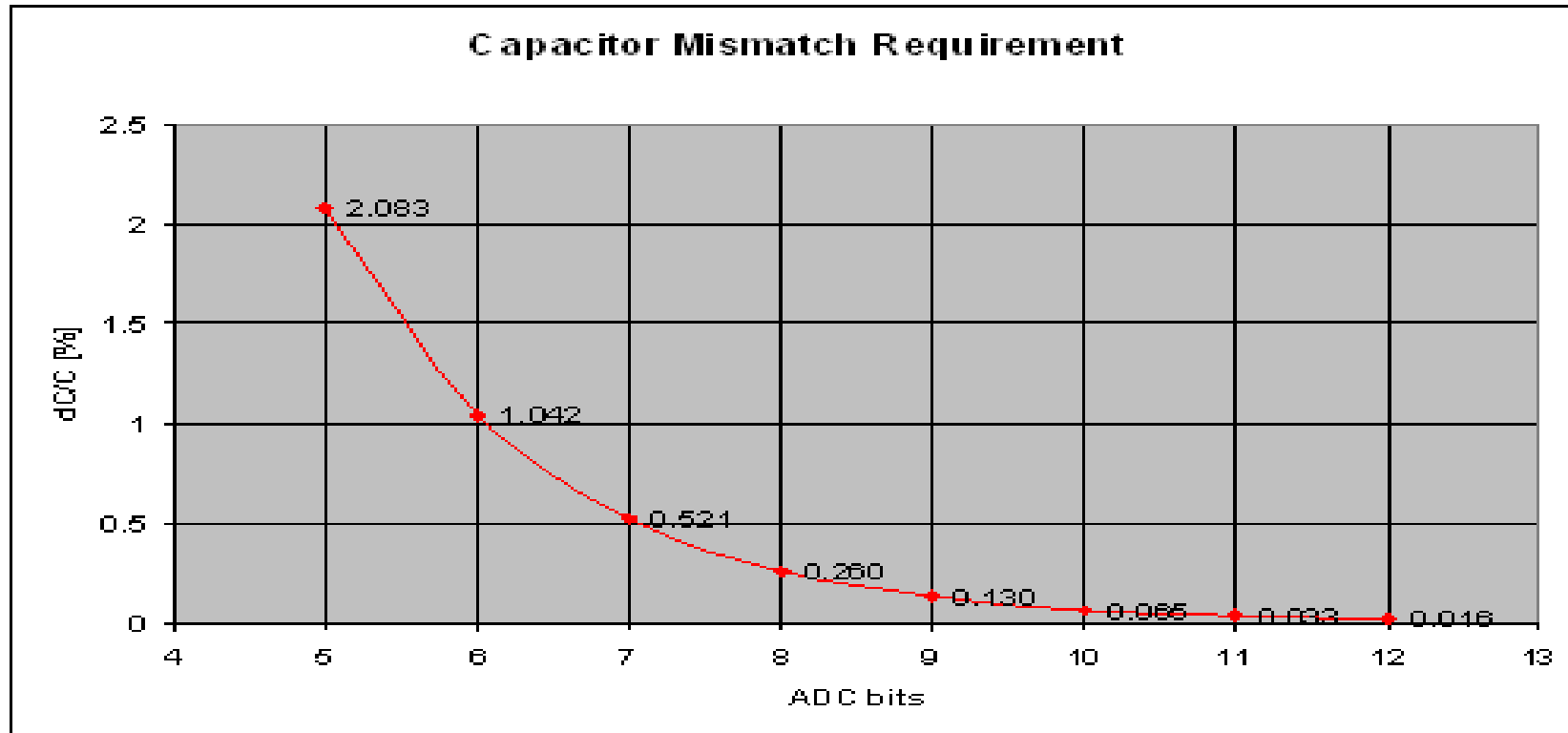
$$C_{LSB} = [C_{unit}] \left[\frac{0.8}{0.518}\right]^2 = 23.85fF$$

$$C_{total} = 97.67pF$$

Not to influency the converter

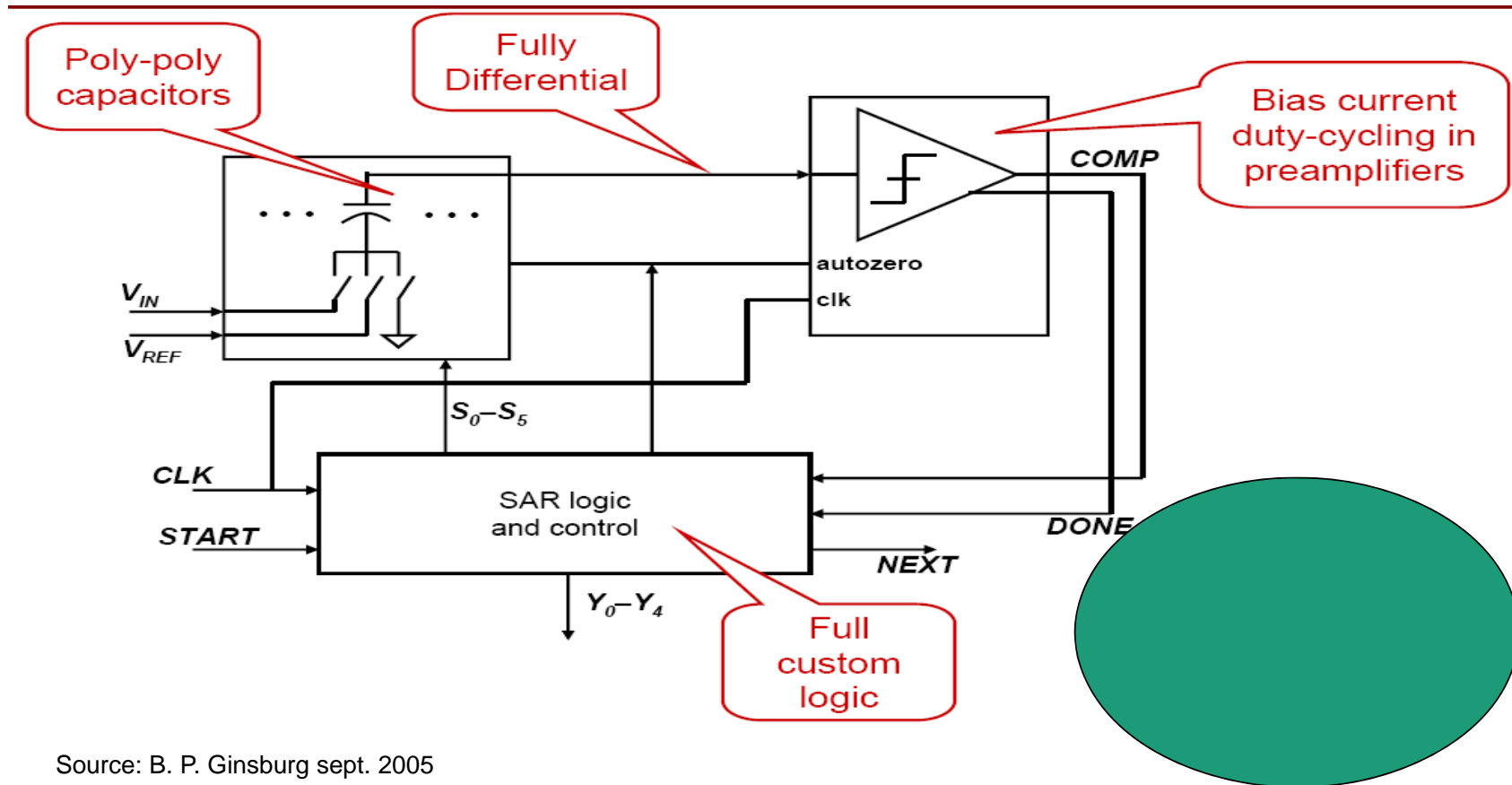
$$C_{LSB} = [C_{unit}] \frac{\left[\left(\frac{\Delta C}{C}\right)_{Full\ scale} \sqrt{2^n - 1}\right]^2}{\left[\left(\frac{\Delta C}{C}\right)_{unit}\right]^2}$$

## Example of Matching Requirement on F. Scale (MSBs)



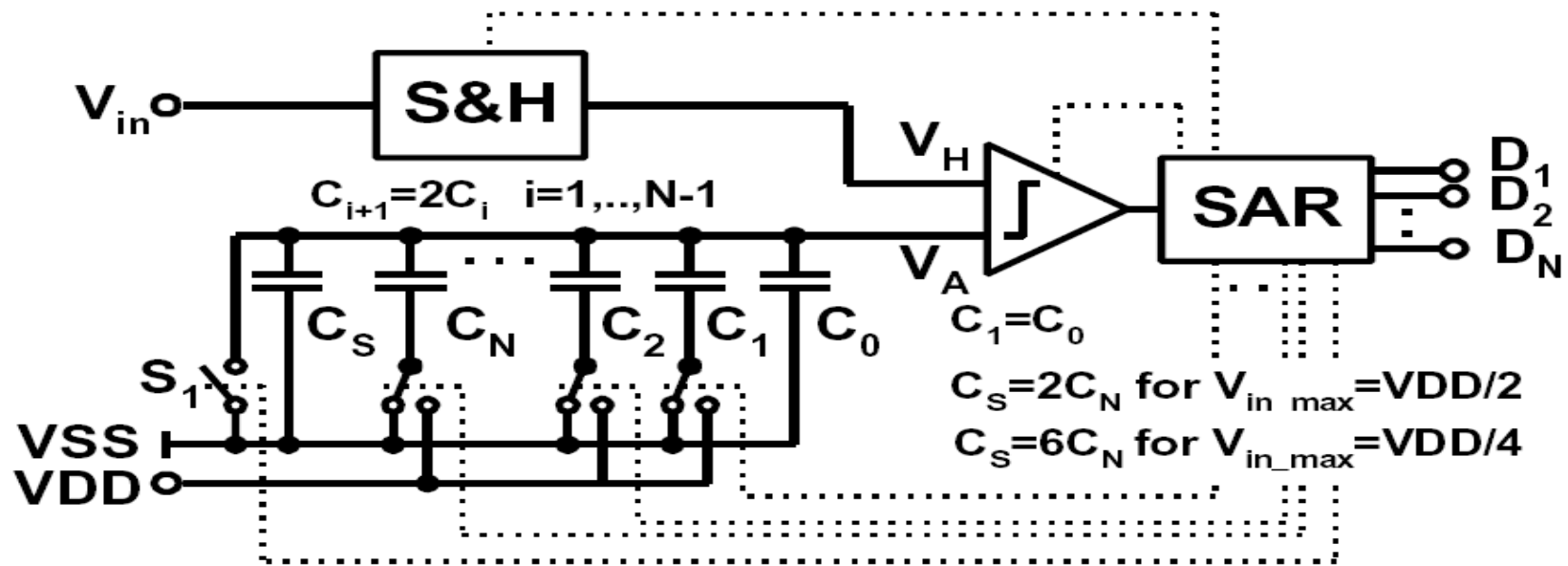
**2 to the  $n \times 2/3$**   
**( $2/3$  only as example not to give all the error to the linearity)**

## How to Build One – What is Needed to Look for



Source: B. P. Ginsburg sept. 2005

# Design Examples



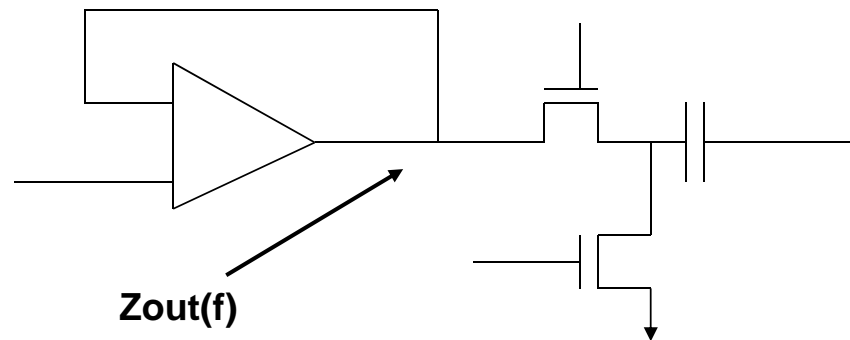
## Word on the References

References issues:

### REFERENCE HOLDING BREF IS HARD TO DO:

During switching phase references has to settle every clock (fast) They are op amp driven therefore make the design almost as op-amp based

Also the comparator must settle every cycle. (faster)



## Summary – C or R DAC

- ❑ Most time absolute value can move  $\pm 15\%$  to  $\pm 20\%$  and does not significantly matter but ratios do
- ❑ However, the bigger the area the better the matching
- ❑ Typical values 30ff can match 3-sigma to better  $\sim 0.5\%$
- ❑ Matching is area dependent generally by the root of  $(W \times L)$
- ❑ In SAR there is contradiction large is good for matching however speed is degraded a lot  $R \text{ switch} \times C$  and its multiplied  $N$  bit for a complete cycle.

## Power / Analog Components

- Without amplifiers power is set by S/H, References, 1 comparator, and digital blocks+clocks
- Generally for lower number of bits – logic may be significant
- Area. For many bits analog set the power waist.
- Logic running multiple times for each conversion and capacitor size (forcing a large drive current)
- Power waist : S/H + Comparator + Reference + Switching/logic

### Good:

- Lowest possible power- FOM**
- Fewer analog elements,**
- T/H or S/H drive low capacitance**

## SAR- Key Points

- ❑ The Feed Back ADC (SAR) offers significant hardware savings compared to flash ADCs because the coarse Quantizer (comparator) resolution  $m$  can be much smaller than the converter resolution.  $N$
  
- ❑ However, its suffer from drawbacks making it not suitable for many applications because:
  - ❑ It requires  $p = N/m$  passes to generate  $N$  bit output words limiting the through put
  - ❑ It requires  $N$ ; bit accurate DAC
  - ❑ It requires faster settling elements
  - ❑ but No need amplifiers !
  
- ❑ **So, if speed is a problem should we combine SARs in time ?– tiem interleaved 50gsps nice to do..**



# End Lecture 7